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Geometrical product specifications (GPS) — Surface texture: Areal —

Part 700:

Calibration, adjustment and verification of areal topography measuring instruments

*Spécification géométrique des produits (GPS) — État de surface:
Surfacique —*

*Partie 700: Étalonnage, ajustage et vérification d'instruments de
mesure de la topographie des surfaces*



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Foreword

ISO (the International Organization for Standardization) is a worldwide federation of national standards bodies (ISO member bodies). The work of preparing International Standards is normally carried out through ISO technical committees. Each member body interested in a subject for which a technical committee has been established has the right to be represented on that committee. International organizations, governmental and non-governmental, in liaison with ISO, also take part in the work. ISO collaborates closely with the International Electrotechnical Commission (IEC) on all matters of electrotechnical standardization.

The procedures used to develop this document and those intended for its further maintenance are described in the ISO/IEC Directives, Part 1. In particular, the different approval criteria needed for the different types of ISO documents should be noted. This document was drafted in accordance with the editorial rules of the ISO/IEC Directives, Part 2 (see www.iso.org/directives).

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For an explanation of the voluntary nature of standards, the meaning of ISO specific terms and expressions related to conformity assessment, as well as information about ISO's adherence to the World Trade Organization (WTO) principles in the Technical Barriers to Trade (TBT), see www.iso.org/iso/foreword.html.

This document was prepared by Technical Committee ISO/TC 213, *Dimensional and geometrical product specifications and verification*, in collaboration with the European Committee for Standardization (CEN) Technical Committee CEN/TC 290, *Dimensional and geometrical product specification and verification*, in accordance with the Agreement on technical cooperation between ISO and CEN (Vienna Agreement).

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Introduction

This document is a geometrical product specification (GPS) standard and is to be regarded as a general GPS standard (see ISO 14638). It influences chain links E, F and G of the chains of standards on profile surface texture and areal surface texture.

The ISO/GPS matrix model given in ISO 14638 gives an overview of the ISO/GPS system, of which this document is a part. The fundamental rules of ISO/GPS given in ISO 8015 apply to this document and the default decision rules given in ISO 14253-1 apply to the specifications made in accordance with this document, unless otherwise indicated.

For more detailed information of the relation of this document to other standards and the GPS matrix model, see [Annex A](#).

In the GPS concept, the design values of geometric parameters on workpieces and their tolerances are compared with the measurement of those parameters on the corresponding manufactured workpieces and their associated measurement uncertainties. For a reliable result it is therefore necessary to calibrate the measurement instrument involved in this process.

This document specifies default procedures for the calibration, adjustment and verification of surface topography measuring instruments, using material measures traceable to the meter through a national metrology institute or qualified laboratory, see ISO/IEC Guide 99:2007, 2.41. Default methods are recommended when no other calibration procedures have been clearly defined.

This document describes the calibration (see ISO/IEC Guide 99:2007, 2.39), adjustment (see ISO/IEC Guide 99:2007, 3.11) and verification (see ISO/IEC Guide 99:2007, 2.44) in general for topography measuring instruments.

The calibration of an instrument's metrological characteristics enables the verification of the instrument's specifications when the specifications are based on these metrological characteristics. This also enables the comparison of systems of different manufacturers that may be based on different measurement principles.

The metrological characteristics capture all of the factors that can influence a measurement result (influence quantities) and can be propagated appropriately through a specific measurement model to estimate measurement uncertainty.

Calibration is a part of the determination of the overall uncertainty of measurement. The complete evaluation of measurement uncertainty may include other factors such as operator variability, changing environmental influences, the effects of thermal and mechanical stresses on the sample part and other factors that are not accounted for in the instrument calibrations.

Alternative calibration techniques to the defaults given here are equally acceptable, depending on the capabilities of the instrumentation and provided those alternatives have clear traceability paths. Example techniques include those based on an independent realization of the meter using a natural emission wavelength, the value for which has been established with a known uncertainty.